On-Wafer Large Signal Pulsed Measurements

J.F. Vidalou, F. Grossier, M. Camiade and J. Obregon. "On-Wafer Large Signal Pulsed Measurements." 1989 MTT-S International Microwave Symposium Digest 89.2 (1989 Vol. II [MWSYM]): 831-834.

Sophisticated design tools are now available for non-linear microwave circuit design. Many simulators have been developed and give reliable results. However, sometimes, predicted results differ from the experimental ones; the difference is generally due to a bad modeling of the active devices used.

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